

Notice of References Cited	Application/Control No. 10/622,379	Applicant(s)/Patent Under Reexamination DEY, APARNA	
	Examiner Neveen Abel-Jalil	Art Unit 2165	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2002/0002524	01-2002	Kossovsky et al.	705/36
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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